EBSD Training Tutorial Workshop 2016 – Monday 23 March 2016

09.30 – 10.00	**Registration and Coffee in the main concourse, Renold Building**	
10.00 – 10.20	Introduction to EBSD	Angus Wilkinson
10.20 – 10.40	Introduction to ECCI	Stefan Zaefferer
10.40 – 11.00	Introduction to Sample Preparation	Michael Hassel-Shearer
11.00 – 11.20	Introduction to Phase Identification	Aimo Winkelmann
11.20 – 11.40	Introduction to Texture Analysis	Klaus Mehnert
11.40 – 12.00	Introduction to Elastic & Plastic Strain Analysis	Ben Britton
12.00 – 12.20	Introduction to Transmission Kikuchi Diffraction	Patrick Trimby
12.20 – 12.40	Introduction to Orientation and Phase Mapping in TEM	Muriel Veron
12.40 – 13.00	Introduction to Data collection, Band detection and Clean up	René de Kloe
13.00 – 14.00	**Sandwich lunch in the main concourse, Renold Building**	
14.00 – 15.30	Sample Preparation for EBSD (Gatan)	Michael Hassel-Shearer and Mark Day
	Orientation and Phase Mapping in TEM – Part 1 (NanoMEGAS)	Muriel Veron
	High speed mapping at low beam currents – using averaging techniques to improve indexing success (EDAX)	René de Kloe
	Acquiring simultaneous EBSD & EDS data from bulk samples (Oxford Instruments)	Keith Dicks and Kim Larsen
	TKD analysis with an on-axis detection system (Bruker)	Daniel Goran
15.30 – 15.45	**Tea and Coffee in the main concourse, Renold Building**	
15.45 – 17.15	Sample Preparation for EBSD (Gatan)	Michael Hassel-Shearer and Mark Day
	Orientation and Phase Mapping in TEM – Part 2 (NanoMEGAS)	Muriel Veron
	High speed mapping at low beam currents – using averaging techniques to improve indexing success (EDAX)	René de Kloe
	Acquiring simultaneous EBSD & EDS data from thin samples (Oxford Instruments)	Kim Larsen and Pat Trimby
	Advanced phase identification using combined EBSD, EDS, dynamical simulations and image correlation (Bruker)	Daniel Goran
17.15	**Workshop Close**	